

**Notice of References Cited**

Application/Control No.

10/617,529

Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL.

Examiner

THANH T. VU

Art Unit

2174

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,246,329	07-2007	Miura et al.	715/810
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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**NON-PATENT DOCUMENTS**

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